CMOS 8-Stage Static Shift Register

Synchronous Parallel or
Serial Input/Serial Output

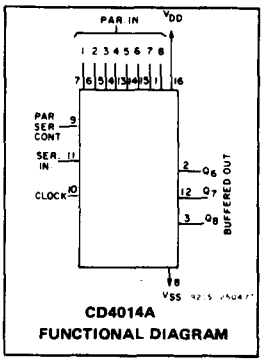
RECOMMENDED OPERATING CONDITIONS at T_A = 25°C, Except as Noted.
For maximum reliability, nominal operating conditions should be selected so that operation is always within the following ranges:

CHARACTERISTIC	V_{DD} (V)	LIMITS				UNITS
		D, F, K, H Packages		*E Package*		
		Min.	Max.	Min.	Max.	
Supply-Voltage Range (For T_A= Full Package-Temperature Range)		3	12	3	12	V
Data Setup Time, t_S	5	350	–	500	–	ns
	10	80	–	100	–	
Clock Pulse Width, t_W	5	500	–	830	–	ns
	10	175	–	200	–	
Clock Input Frequency, f_{CL}	5	dc	1	dc	0.6	MHz
	10	dc	3	dc	2.5	
Clock Rise and Fall Time, t_rCL, t_fCL*	5	–	15	–	15	μs
	10	–	5	–	5	

* If more than one unit is cascaded t_rCL should be made less than or equal to the sum of the transition time and the fixed propagation delay of the output of the driving stage for the estimated capacitive load.

STATIC ELECTRICAL CHARACTERISTICS

Characteristic	Conditions			Limits at Indicated Temperatures (°C)								Units
				D, F, K, H Packages				*E Package*				
	V_O (V)	V_{IN} (V)	V_{DD} (V)	−55	+25 Typ.	+25 Limit	+125	−40	+25 Typ.	+25 Limit	+85	
Quiescent Device Current I_L Max.	–	–	5	5	0.5	5	300	50	0.5	50	700	μA
	–	–	10	10	1	10	600	100	1	100	1400	
	–	–	15	50	1	50	2000	500	5	500	5000	
Output Voltage: Low-Level, V_{OL}	–	5	5	0 Typ.; 0.05 Max.								V
	–	10	10	0 Typ.; 0.05 Max.								
High Level V_{OH}	–	0	5	4.95 Min.; 5 Typ.								
	–	0	10	9.95 Min.; 10 Typ.								
Noise Immunity: Inputs Low, V_{NL}	4.2	–	5	1.5 Min.; 2.25 Typ.								V
	9	–	10	3 Min.; 4.5 Typ.								
Inputs High V_{NH}	0.8	–	5	1.5 Min.; 2.25 Typ.								
	1	–	10	3 Min.; 4.5 Typ.								
Noise Margin: Inputs Low, V_{NML}	4.5	–	5	1 Min.								V
	9	–	10	1 Min.								
Inputs High, V_{NMH}	0.5	–	5	1 Min.								
	1	–	10	1 Min.								
Output Drive Current: n-Channel (Sink), I_DN Min.	0.5	–	5	0.15	0.3	0.12	0.085	0.072	0.3	0.06	0.05	mA
	0.5	–	10	0.31	0.5	0.25	0.175	0.12	0.5	0.1	0.08	
p-Channel (Source): I_DP Min.	4.5	–	5	-0.1	-0.16	-0.08	-0.055	-0.06	-0.16	-0.05	-0.04	
	9.5	–	10	-0.25	-0.44	-0.20	-0.14	-0.12	-0.44	-0.1	-0.08	
Input Leakage Current, I_{IL}, I_{IH}	Any Input	–	15	$\pm 10^{-5}$ Typ.; ±1 Max.								μA



CD4014A
FUNCTIONAL DIAGRAM

The RCA-CD4014A types are 8-stage parallel-input/serial output registers having common CLOCK and PARALLEL/SERIAL CONTROL INPUTS, a single SERIAL DATA INPUT, and individual parallel "JAM" INPUTS to each register stage. Each register stage is a D-type, master-slave flip-flop. In addition to an output from stage 8, "Q" outputs are also available from stages 6 and 7. Parallel as well as serial entry is made into the register synchronous with the positive clock line transition and under control of the PARALLEL/SERIAL CONTROL input. When the PARALLEL/SERIAL CONTROL input is low, data is serially shifted into the 8-stage register synchronously with the positive transition of the clock line. When the PARALLEL/SERIAL CONTROL input is high, data is jammed into the 8-stage register via the parallel input lines and synchronous with the positive transition of the clock line. Register expansion using multiple CD4014A packages is permitted.

These types are supplied in 16-lead hermetic dual-in-line ceramic packages (D and F suffixes), 16-lead dual-in-line plastic packages (E suffix), 16-lead ceramic flat packages (K suffix), and in chip form (H suffix).

CL ▲	SER. IN	PAR SER CONTROL	PI-1	PI-n	Q_1 (INTERNAL)	Q_n	
⌐	X	1	0	0	0	0	
⌐	X	1	1	0	1	0	
⌐	X	1	0	1	0	1	
⌐	X	1	1	1	1	1	
⌐	0	0	X	X	0	Q_n-1	
⌐	1	0	X	X	1	Q_n-1	
⌙	X	X	X	X	Q_1	Q_n	NC

X = DON'T CARE CASE ▲ = LEVEL CHANGE
NC = NO CHANGE

Fig. 1 – Truth table.

Features:

- Medium speed operation. . . . . 5 MHz (typ.) clock rate at $V_{DD} - V_{SS} = 10$ V
- Fully static operation
- 8 master-slave flip-flops plus output buffering and control gating
- Quiescent current specified to 15 V
- Maximum input leakage current of 1 μA at 15 V (full package-temperature range)
- 1-V noise margin (full package-temperature range)

Applications:

- Synchronous parallel input/serial output data queueing
- Parallel to serial data conversion
- General-purpose register

DYNAMIC ELECTRICAL CHARACTERISTICS at $T_A = 25°C$, Input t_r, $t_f = 20$ ns, $C_L = 15$ pF, $R_L = 200$ kΩ

CHARACTERISTIC	TEST CONDITIONS	LIMITS						UNITS
		D, F, K, H Packages			*E Package*			
	V_{DD} (V)	Min.	Typ.	Max.	Min.	Typ.	Max.	
Propagation Delay Time; t_{PLH}, t_{PHL}	5	–	300	750	–	300	1000	ns
	10	–	100	225	–	100	300	
Transition Time; t_{THL}, t_{TLH}	5	–	150	300	–	150	400	ns
	10	–	75	125	–	75	150	
Maximum Clock Input Frequency, f_{CL}	5	1	2.5	–	0.6	2.5	–	MHz
	10	3	5	–	2.5	5	–	
Minimum Clock Pulse Width, t_W	5	–	200	500	–	200	830	ns
	10	–	100	175	–	100	200	
Clock Rise & Fall Time; t_rCL, t_fCL*	5	–	–	15	–	–	15	μs
	10	–	–	5	–	–	5	
Minimum Data Set Up Time, t_S	5	–	100	350	–	100	500	ns
	10	–	50	80	–	50	100	
Average Input Capacitance, C_I	Any Input	–	5	–	–	5	–	pF

* If more than one unit is cascaded t_rCL should be made less than or equal to the sum of the transition time and the fixed propagation delay of the output of the driving stage for the estimated capacitive load.

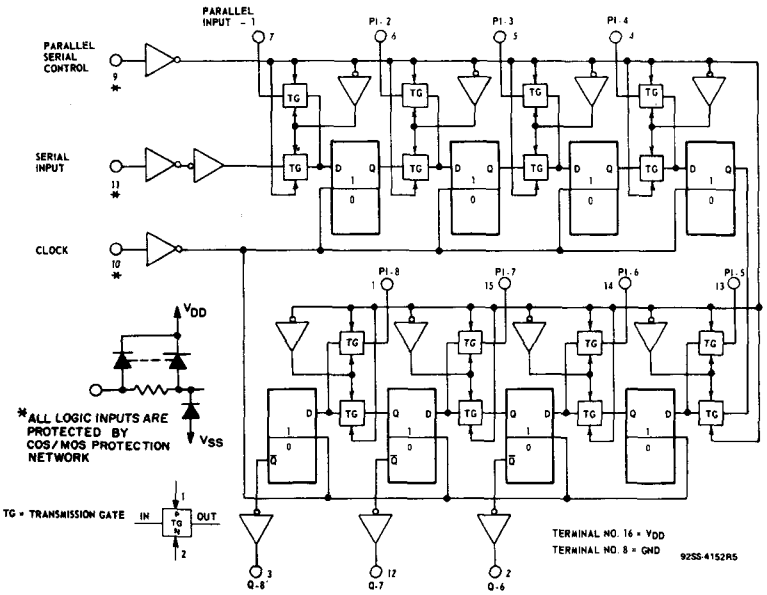


Fig. 5 – Logic block diagram.

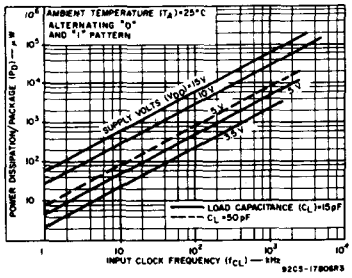


Fig. 2 – Typical dissipation characteristics.

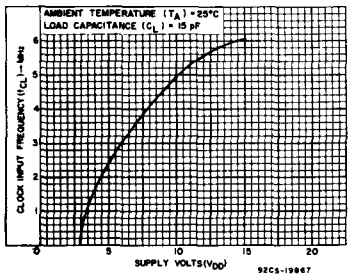


Fig. 3 – Typical clock input frequency vs. supply voltage.

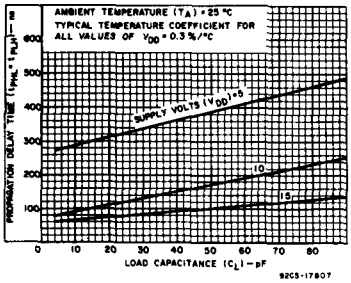


Fig. 4 – Typical propagation delay time vs. load capacitance.

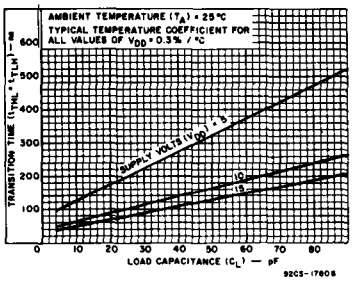


Fig. 6 – Typical transition time vs. load capacitance.